

Notice of References Cited

Application/Control No.

10/592,957

Applicant(s)/Patent Under
Reexamination
UEDA ET AL.

Examiner

HUYEN D. LE

Art Unit

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-6,529,611 | 03-2003 | Kobayashi et al. | 381/396 |
| * | B | US-6,611,605 | 08-2003 | Kim, Jeong Uk | 381/406 |
| * | C | US-6,996,246 | 02-2006 | Ito, Masanori | 381/398 |
| * | D | US-7,043,045 | 05-2006 | Takahashi, Osamu | 381/398 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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